

Notice of References Cited	Application/Control No. 10/609,142	Applicant(s)/Patent Under Reexamination ZAIKIN ET AL.	
	Examiner Constantine Hannaher	Art Unit 2878	Page 1 of 2

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0036875 A1	02-2003	Peck et al.	702/127
	B	US-			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	Examiner Constantine Hannaher	Art Unit 2878	Page 2 of 2

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